## Notice of References Cited Application/Control No. 09/661,306 Examiner Demetria A. Williams Applicant(s)/Patent Under Reexamination ABE ET AL. Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	А	US-6,501,811	12-2002	Yamada, Kunihiro	375/355
	В	US-5,796,787	08-1998	Chen et al.	375/362
	С	US-6,366,629	04-2002	Chen et al.	375/355
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	κ	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*	v	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	ρ					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	<b>V</b>						
	8						
	x						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.